

**Contact-distance transformer, electric testing device and method
for producing a contact-distance transformer**

Abstract

The invention refers to a contact-distance transformer (4) of an electric testing device (1) for testing an electric specimen (7), in particular a wafer (8), wherein said contact-distance transformer (4) is used to reduce the distance between neighboring electric contacts (16, 19), and is provided with a non-electrically conductive supporting structure (28), which is provided with a first side (17) and a second side (18), wherein on the first side (17) first electric contacts (16) are positioned at a contact distance (a) to each other, and on the second side (18) second electric contacts (19) are positioned, which have a contact distance (b) to each other which is smaller than the first contacts (16) on the first side (17), wherein the first contacts (16) are connected to the second contacts (19) by means of electric connections (20) which pass through the support structure (28) and/or which are positioned on the support structure (28). It is envisaged that both the support structure (28) and the electric connections (20) are formed as 3D-printed components (27). Moreover, the invention refers to an electric testing device (1) as well as to a method for producing a contact-distance transformer (4).

(Figure 1)